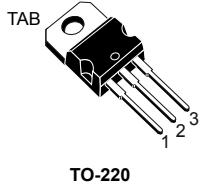


N-channel 550 V, 150 mΩ typ., 16 A MDmesh M5 Power MOSFET in a TO-220 package

Features



Order code	V_{DS} at T_J max.	$R_{DS(on)}$ max.	I_D
STP18N55M5	600 V	192 mΩ	16 A

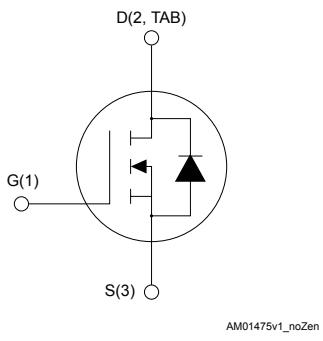
- Extremely low $R_{DS(on)}$
- Low gate charge and input capacitance
- Excellent switching performance
- 100% avalanche tested

Applications

- Switching applications

Description

This device is an N-channel Power MOSFET based on the MDmesh M5 innovative vertical process technology combined with the well-known PowerMESH horizontal layout. The resulting product offers extremely low on-resistance, making it particularly suitable for applications requiring high power and superior efficiency.



Product status link

[STP18N55M5](#)

Product summary

Order code	STP18N55M5
Marking	18N55M5
Package	TO-220
Packing	Tube

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{GS}	Gate-source voltage	± 25	V
I_D	Drain current (continuous) at $T_C = 25^\circ\text{C}$	16	A
	Drain current (continuous) at $T_C = 100^\circ\text{C}$	10	
$I_{DM}^{(1)}$	Drain current (pulsed)	64	A
P_{TOT}	Total power dissipation at $T_C = 25^\circ\text{C}$	110	W
$dv/dt^{(2)}$	Peak diode recovery voltage slope	15	V/ns
T_{stg}	Storage temperature range	-55 to 150	$^\circ\text{C}$
T_J	Operating junction temperature range		$^\circ\text{C}$

1. Pulse width is limited by safe operating area.
2. $I_{SD} \leq 16 \text{ A}$, $di/dt \leq 400 \text{ A}/\mu\text{s}$, $V_{DS} (\text{peak}) < V_{(BR)DSS}$, $V_{DD} = 340 \text{ V}$.

Table 2. Thermal data

Symbol	Parameter	Value	Unit
R_{thJC}	Thermal resistance, junction-to-case	1.14	$^\circ\text{C}/\text{W}$
R_{thJA}	Thermal resistance, junction-to-ambient	62.5	$^\circ\text{C}/\text{W}$

Table 3. Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AR}	Avalanche current, repetitive or non-repetitive (pulse width limited by T_J max.)	4	A
E_{AS}	Single pulse avalanche energy (starting $T_J = 25^\circ\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50 \text{ V}$)	210	mJ

2 Electrical characteristics

$T_C = 25^\circ\text{C}$ unless otherwise specified.

Table 4. On/off states

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$I_D = 1 \text{ mA}, V_{GS} = 0 \text{ V}$	550			V
I_{DSS}	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 550 \text{ V}$			1	μA
		$V_{GS} = 0 \text{ V}, V_{DS} = 550 \text{ V}, T_C = 125^\circ\text{C}$ ⁽¹⁾			100	
I_{GSS}	Gate body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			± 100	nA
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	3	4	5	V
$R_{\text{DS(on)}}$	Static drain-source on resistance	$V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}$		150	192	$\text{m}\Omega$

1. Specified by design, not tested in production.

Table 5. Dynamic

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$	-	1260	-	pF
C_{oss}	Output capacitance		-	42	-	pF
C_{rss}	Reverse transfer capacitance		-	3.6	-	pF
$C_{\text{o(tr)}}^{(1)}$	Equivalent capacitance time related	$V_{DS} = 0 \text{ to } 440 \text{ V}, V_{GS} = 0 \text{ V}$	-	103	-	pF
$C_{\text{o(er)}}^{(2)}$	Equivalent capacitance energy related		-	35	-	pF
R_g	Gate input resistance		-	2.8	-	Ω
Q_g	Total gate charge	$V_{DD} = 440 \text{ V}, I_D = 8 \text{ A}, V_{GS} = 0 \text{ to } 10 \text{ V}$ (see Figure 15. Test circuit for gate charge behavior)	-	31	-	nC
Q_{gs}	Gate-source charge		-	8.3	-	nC
Q_{gd}	Gate-drain charge		-	14.2	-	nC

- Time related is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS} .
- Energy related is defined as a constant equivalent capacitance giving the same stored energy as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS} .

Table 6. Switching times

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit
$t_{d(v)}$	Voltage delay time	$V_{DD} = 400 \text{ V}, I_D = 10.5 \text{ A}, R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see Figure 16. Test circuit for inductive load switching and diode recovery times and Figure 19. Switching time waveform)	-	37	-	ns
$t_{r(v)}$	Voltage rise time		-	7	-	ns
$t_{c(\text{off})}$	Crossing time		-	10.3	-	ns
$t_{f(i)}$	Current fall time		-	8.3	-	ns

Table 7. Source drain diode

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		16	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		64	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 16 \text{ A}, V_{GS} = 0 \text{ V}$	-		1.5	V
t_{rr}	Reverse recovery time	$I_{SD} = 16 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}$,	-	244		ns
Q_{rr}	Reverse recovery charge	$V_{DD} = 100 \text{ V}$ (see Figure 16. Test circuit for inductive load switching and diode recovery times)	-	2.8		μC
I_{RRM}	Reverse recovery current	$I_{SD} = 16 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}$ (see Figure 16. Test circuit for inductive load switching and diode recovery times)	-	23		A
t_{rr}	Reverse recovery time	$V_{DD} = 100 \text{ V}, T_J = 150 \text{ }^\circ\text{C}$	-	295		ns
Q_{rr}	Reverse recovery charge		-	3.7		μC
I_{RRM}	Reverse recovery current		-	25		A

1. Pulse width limited by safe operating area.
2. Pulsed: pulse duration = 300 μs , duty cycle 1.5%.

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

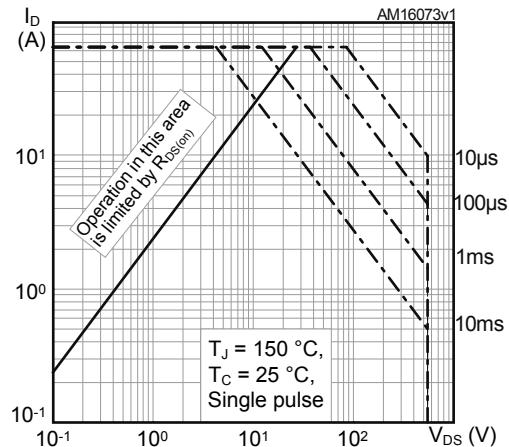


Figure 2. Thermal impedance

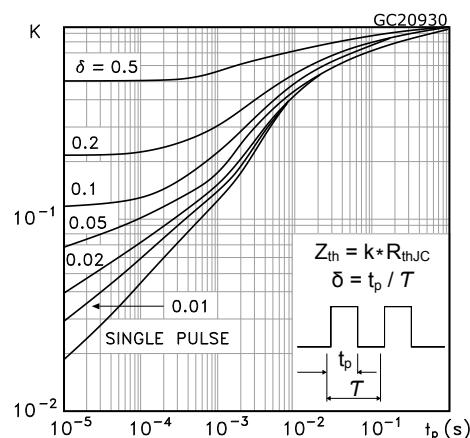


Figure 3. Output characteristics

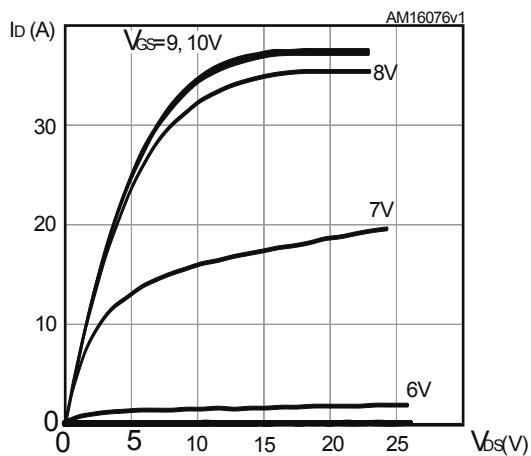


Figure 4. Transfer characteristics

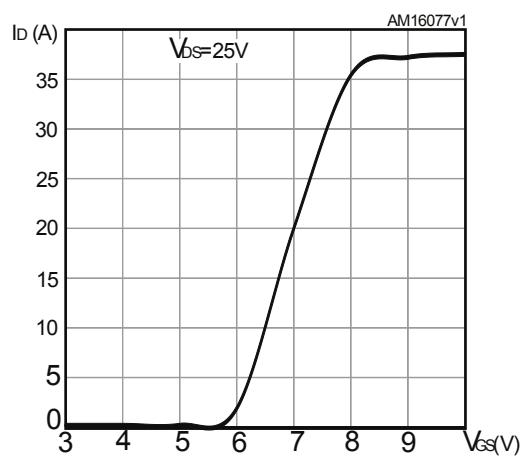


Figure 5. Gate charge vs gate-source voltage

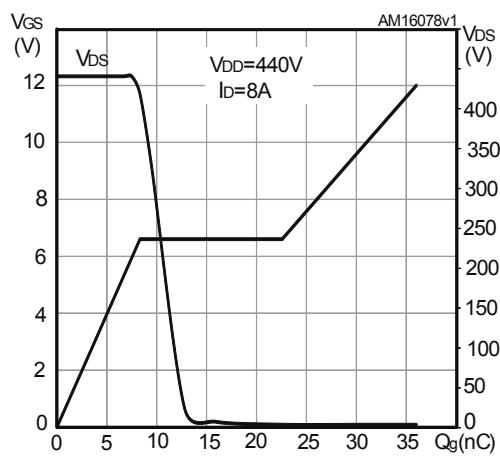


Figure 6. Static drain-source on resistance

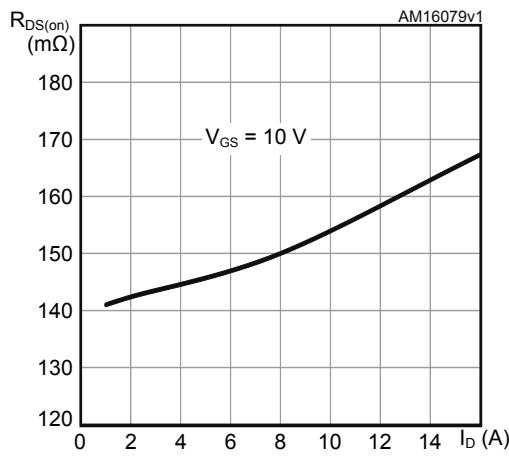


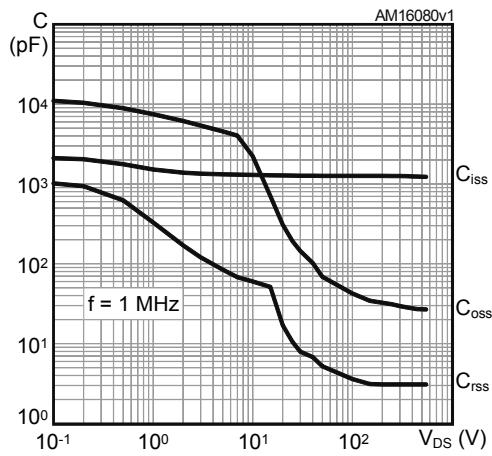
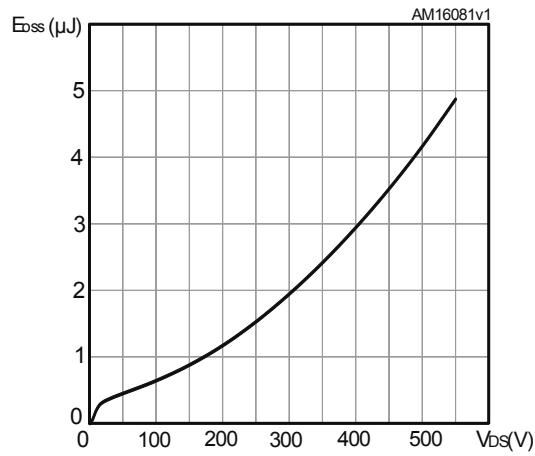
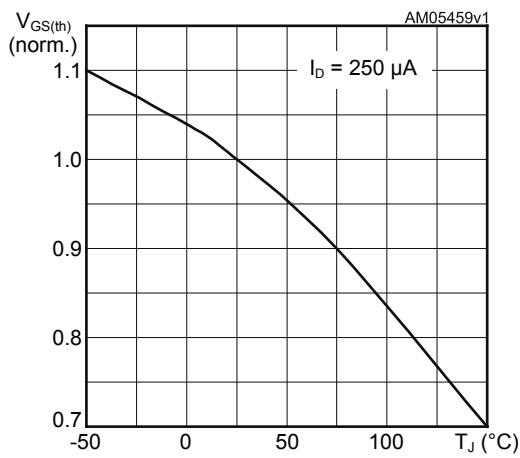
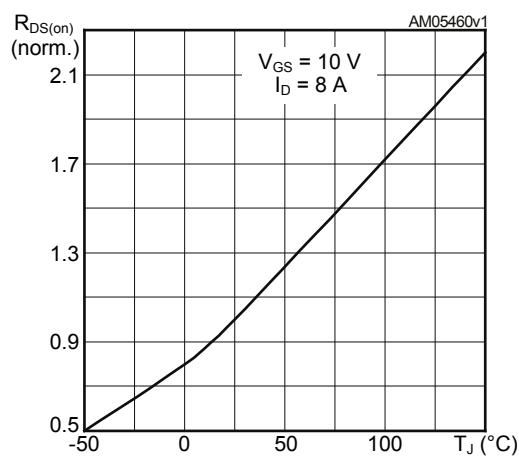
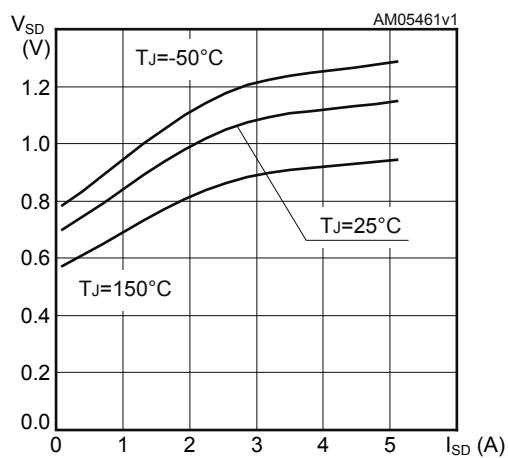
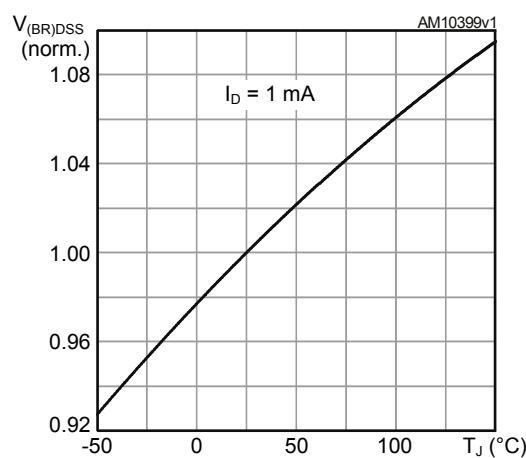
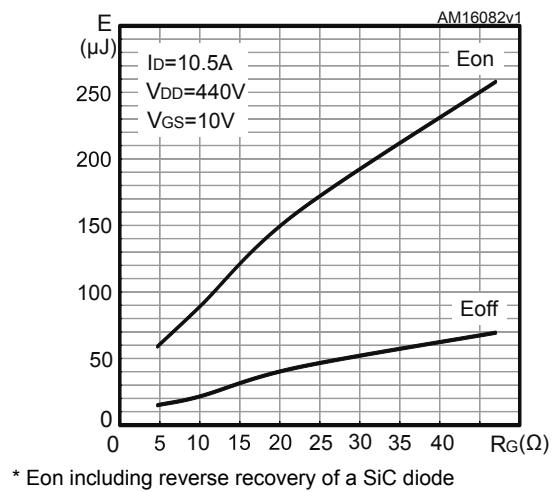
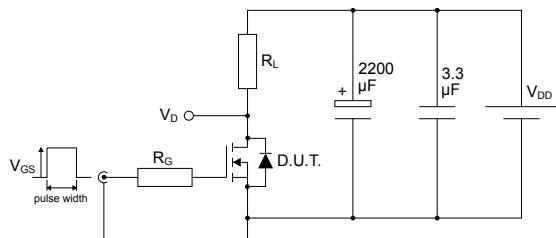
Figure 7. Capacitance variations

Figure 8. Output capacitance stored energy

Figure 9. Normalized gate threshold voltage vs temperature

Figure 10. Normalized on-resistance vs temperature

Figure 11. Drain-source diode forward characteristics

Figure 12. Normalized $V_{(BR)DSS}$ vs temperature


Figure 13. Switching energy vs gate resistance

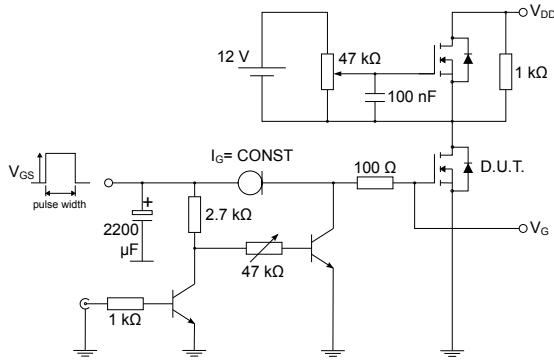
3 Test circuits

Figure 14. Test circuit for resistive load switching times



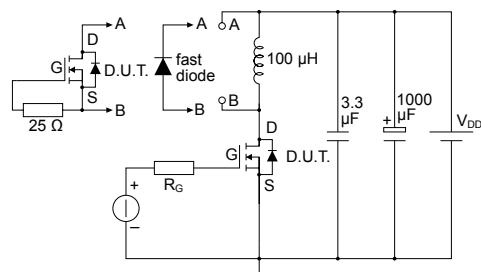
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Figure 15. Test circuit for gate charge behavior



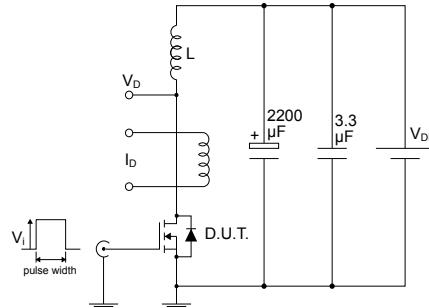
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Figure 16. Test circuit for inductive load switching and diode recovery times



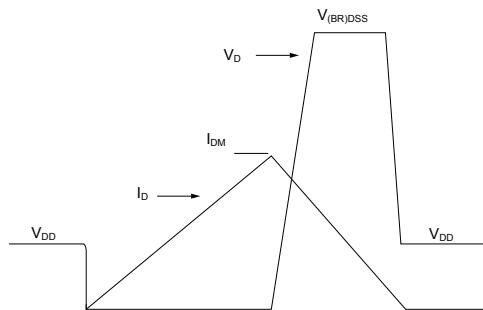
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Figure 17. Unclamped inductive load test circuit



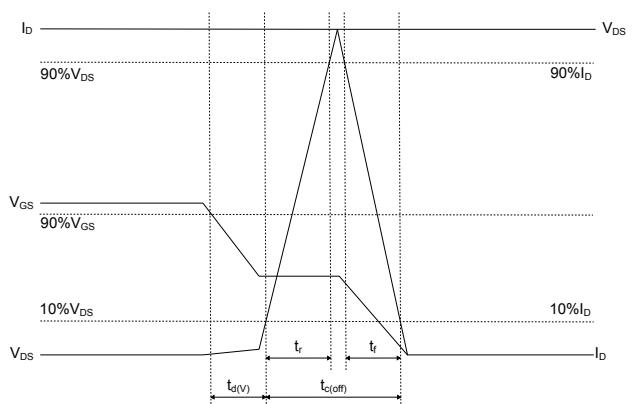
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Figure 18. Unclamped inductive waveform



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Figure 19. Switching time waveform



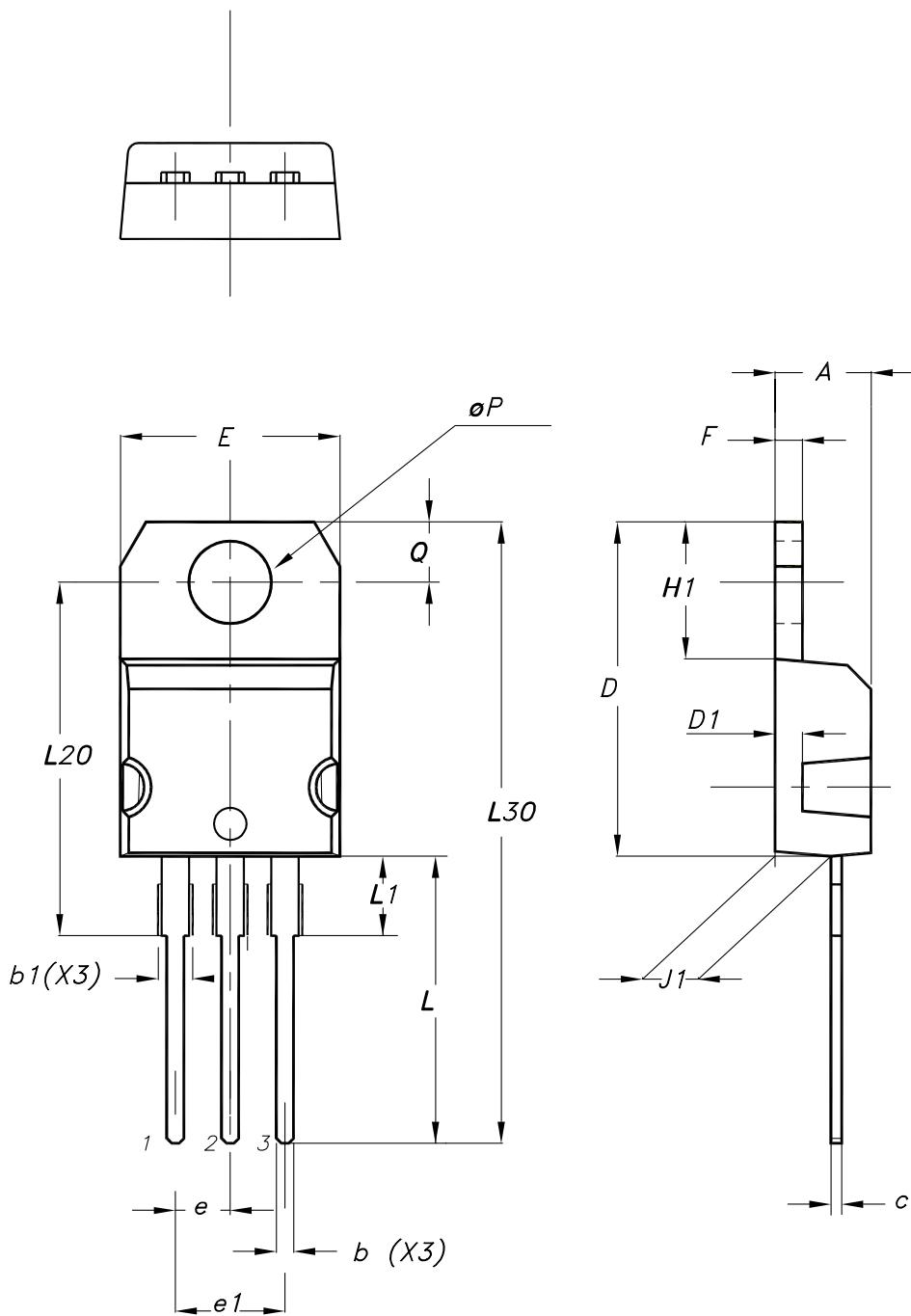
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4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

4.1 TO-220 type A package information

Figure 20. TO-220 type A package outline



0015988_typeA_Rev_23

Table 8. TO-220 type A package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
b	0.61		0.88
b1	1.14		1.55
c	0.48		0.70
D	15.25		15.75
D1		1.27	
E	10.00		10.40
e	2.40		2.70
e1	4.95		5.15
F	1.23		1.32
H1	6.20		6.60
J1	2.40		2.72
L	13.00		14.00
L1	3.50		3.93
L20		16.40	
L30		28.90	
øP	3.75		3.85
Q	2.65		2.95
Slug flatness		0.03	0.10

Revision history

Table 9. Document revision history

Date	Revision	Changes
31-Aug-2023	1	First release. The part number STP18N55M5 was previously inserted in the DS6705.

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4.1	TO-220 type A package information	9
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